Cypress Semiconductor Corporation, 198 Champion Court, San Jose, CA 95134. Tel: (408) 943-2600

PRODUCT CHANGE NOTIFICATION

PCN: PCN183702 **Date:** September 12, 2018

Subject: Qualification of Tera Probe, Inc. Japan as an Additional Wafer Test (Sort) Site for Flash NOR FL128S and FL512S Products

To: TOKYO ELECTRON DEVICE

cy-pcn@teldevice.co.jp

Change Type: Major

Description of Change:
Cypress announces the qualification of Tera Probe, Inc. Japan as an additional wafer-level test (sort) site for FL128S and FL512S products. These products are currently being tested on the Verigy V5400 test platform at Test 25 in Austin, Texas and are now qualified on the Advantest 5830 test platform at Tera Probe, Inc. There are no changes to the test coverage and methodology.

This qualification will allow Cypress to leverage Tera Probe's manufacturing expertise with quality focus. This in turn also provides the means for Cypress to continue to meet its customers' IC testing needs as well as delivery commitments in dynamic, changing market conditions. Tera Probe, Inc. is certified on several international quality standards: ISO / TS16949, ISO 9001, ISO 14001 and OHSAS 18001. Tera Probe's certificates can be viewed on their corporate web site: http://www.teraprobe.com/english/corporate/iso.html

Cypress qualification is in compliance with JEDEC and AEC standards. To help expedite the implementation of this site, please share any additional customer specific qualification and test requirements at the earliest.

Benefit of Change:
Cypress will have the added capability to meet varying market demand, and to ensure consistent and reliable delivery performance to customers. Immediate adoption of Tera Probe material will also help secure material and minimize supply interruption in the future.

Part Numbers Affected: 219
See the attached 'Affected Parts List' file for a list of all part numbers affected by this change.

Qualification Status:
This wafer sort site has been qualified through a series of tests documented in the Qualification Test Plans summarized in the table below. These qualification reports can be found as attachments to this PCN or by visiting www.cypress.com and typing the QTP number in the keyword search window.

QTP Number	Qualification
182911	Sort Site Addition of Tera Probe Advantest T5830 FL512S Products
182912	Sort Site Addition of Tera Probe Advantest T5830 FL128S Products

Completion dates for internal qualification are provided in the table below:

Cypress Qualification	PCN Publication Date	Implementation Date
August 23, 2018	September 12, 2018	September 28, 2018

Approximate Implementation Date:
Effective 15 days from the date of this notification or upon customer approval, whichever comes first, all shipments of Commercial, Industrial and Automotive non-PPAP part numbers in the attached file will be sorted at Tera Probe, Inc. Japan or other approved wafer sort sites.

For Automotive PPAP part numbers this change will be effective upon customer approval.

Anticipated Impact:
No impact is expected to form, fit, function, datasheet parameters, package composition or package pin-out.

Method of Identification:
Cypress maintains traceability of product to wafer level, including wafer fabrication location, through the lot number marked on the package.

Response Required:
Please share any additional qualification and test requirements if needed.

For additional information regarding this change, contact your local sales representative or contact the PCN Administrator at pcn_adm@cypress.com.

Sincerely,

Cypress PCN Administration